



2006 Workshop on Microelectronics and Electron Devices (WMED-2006)

*Fourth Regional Meeting, Boise Center on the Grove, Boise, Idaho, April 14, 2006
IEEE Electron Devices Society*

The Fourth Annual Workshop on Microelectronics and Electron Devices will provide a forum for reviewing and discussing all aspects of microelectronics including processing, electrical characterization, design, and new device technologies. This symposium will consist of both invited and contributed talks and papers as well as a poster session throughout the afternoon. Faculty, students, and researchers in industry are encouraged to contribute presentations on either completed research or “work-in-progress” research. Topics are in the following areas that will form the contributing sessions and poster sessions in the workshop program:

- **Microelectronic Device Processing and Process Integration**
Trends in submicron technologies; product development (DRAM, SRAM, Flash, imagers); new technologies (phase change memory, FeRAM, carbon nanotubes); novel transistors; transistor and capacitor improvements.
- **Microelectronic Device Electrical Testing and Reliability Testing**
Dielectric reliability; device reliability; phase change memory reliability; novel memory technology testing schemes; electrical properties of novel devices.
- **Microelectronic Packaging and MEMS**
Novel packaging structures and materials; MEMS sensors.
- **Microelectronic Circuit Design**
New product design; design techniques; memory sensing schemes.

An IEEE Publication of the accepted papers and a CDROM including the papers and presentations is planned and will be available at the start of the meeting. Submitted papers will be limited to two pages and should follow the IEEE Electron Device Letters publication format guidelines. A file containing manuscript preparation instructions can be downloaded at:

www.ieee.org/portal/cms_docs/pubs/transactions/auinfo03.pdf

Final manuscripts should be submitted electronically at the website listed below by **March 17, 2006**:

<http://www.ieee.org/organizations/pubs/confpub/wmed06/authors/>

A peer review process of the submitted papers will determine the oral/poster presentations based on the submitted two page papers.

Questions concerning papers or paper submissions can be directed to: Kris Campbell (Publications Chair), kriscampbell@boisestate.edu. Other questions regarding the conference can be directed to Roy Meade (General Chair, IEEE Electron Device Society, Boise Section), rmeade@micron.com.